

DXG1CH27A-140EF

RF POWER GaN Transistor for Wireless Infrastructure

2515 – 2675 MHz, 140 W,
RF POWER GaN Transistor

DXG1CH27A-140EF is a 140 W RF GaN HEMT Transistor with first generation RF GaN technology from Dynax, which is ideal for 2515 MHz to 2675 MHz cellular base station applications. It features input matching, wide instantaneous bandwidth and a thermally-enhanced package.

Features

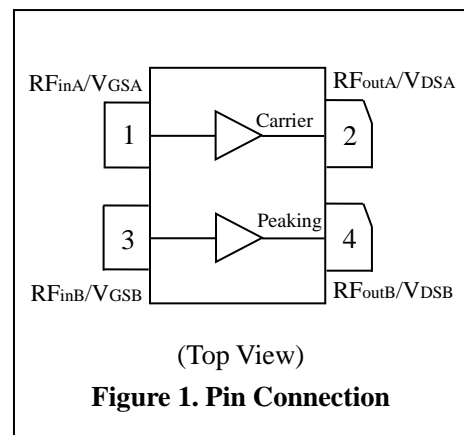
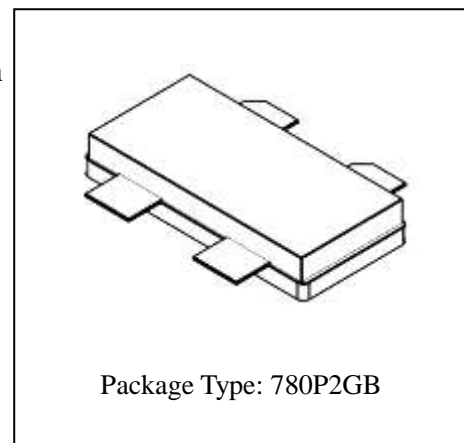
- High Efficiency, High Gain
- Internally Matched for Broadband Performance
- Designed for Digital Pre-Distortion Error Correction Systems
- Optimized for Doherty Applications

Typical RF Performance ¹

- Frequency: 2515 – 2675 MHz
- Peak Output Power: 140 W
- Linear Efficiency: > 51 %
- Linear Gain: > 13 dB
- ACPR: < - 28 dBc

Note:

¹Typical Doherty Performance in Dynax DXG1CH27A-140EF Doherty Demo with the device soldered to the heatsink, test condition: $V_{DD} = 48$ V, $I_{DQA} = 100$ mA, $V_{GSB} = -3.5$ V, $P_{out} = 14$ W Avg., 1-Carrier W-CDMA, Input Signal PAR = 7.5 dB @ 0.01 % Probability on CCDF.



PRELIMINARY

Table 1. Maximum Ratings

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V _{DSS}	150	V
Gate-Source Voltage	V _{GS}	-10 ~ +2	V
Maximum Forward Gate Current	I _{GMAX}	13.6	mA
Storage Temperature Range	T _{STG}	-65 ~ +150	°C
Operating Junction Temperature	T _J	225	°C
Absolute Maximum Channel Temperature ²	T _{MAX}	275	°C

² Functional operation above 225 °C has not been characterized and is not implied. Operation at T_{MAX} (275 °C) reduces median time to failure by an order of magnitude; operation beyond T_{MAX} could cause permanent damage.

Table 2. Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance at Average Power by Infrared Measurement, Active Die Surface-to-Case Case Temperature 85 °C, P _D = 13.5 W	R _{thjc(IR)}	2.1	°C/W
Thermal Resistance at Average Power by Finite Element Analysis, Junction-to-Case Case Temperature 85 °C, P _D = 13.5 W	R _{thjc(FEA)}	2.8	°C/W

Table 3. Ruggedness Characteristics

VSWR 10:1 at V _{DD} = 48 V, 140 W Pulsed CW Output Power, Pulse Width = 100 us, Duty = 10%	No Device Damage
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Table 4. Ordering Information

Device	Package Number	Marking
DXG1CH27A-140EF	780P2GB	DXG1CH27A-140EF

Table 5. Bias Sequences

Bias-up Sequence	Bias-down Sequence
Set V _{GS} to -5 V	Turn off RF power
Turn on V _{DS} to 48 V	Reduce V _{DS} down to 0 V
Increase V _{GS} until I _{DS} current is attained	Turn off V _{GS}
Apply RF input power	

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Table 6. Electrical Characteristics ($T_A = 25\text{ }^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min.	Typ.	Max.	Unit
DC Characteristics (measured on wafer prior to packaging)					
Side A, Carrier					
Drain-Source Leakage Current ($V_{GS} = -10\text{ V}$, $V_{DS} = 150\text{ V}$)	I_{DSS}	-	-	5.0	mA
Drain-Source Breakdown Voltage ($V_{GS} = -10\text{ V}$, $I_D = 5.0\text{ mA}$)	$V_{(BR)DSS}$	150	-	-	V
Gate Threshold Voltage ($V_{DS} = 10\text{ V}$, $I_D = 5.0\text{ mA}$)	$V_{GS(th)}$	-4.0	-2.1	-1.0	V
Gate Quiescent Voltage ($V_{DD} = 48\text{ V}$, $I_D = 125\text{ mA}$)	$V_{GS(Q)}$	-	-1.7	-	V
Side B, Peaking					
Drain-Source Leakage Current ($V_{GS} = -10\text{ V}$, $V_{DS} = 150\text{ V}$)	I_{DSS}	-	-	8.6	mA
Drain-Source Breakdown Voltage ($V_{GS} = -10\text{ V}$, $I_D = 8.6\text{ mA}$)	$V_{(BR)DSS}$	150	-	-	V
Gate Threshold Voltage ($V_{DS} = 10\text{ V}$, $I_D = 8.6\text{ mA}$)	$V_{GS(th)}$	-4.0	-2.1	-1.0	V
Gate Quiescent Voltage ($V_{DD} = 48\text{ V}$, $I_D = 200\text{ mA}$)	$V_{GS(Q)}$	-	-1.7	-	V
RF Characteristics					
Typical Doherty Performance³					
Power Gain	G_p	-	13	-	dB
Drain Efficiency	η_D	-	51	-	%
Output Peak-to-Average Ratio @ 0.01% Probability on CCDF	PAR	-	7.5	-	dB
Adjacent Channel Power Ratio	ACPR	-	-28	-	dBc

³Typical Doherty Performance in Dynax DXG1CH27A-140EF Doherty Demo with the device soldered to the heatsink, test condition: $V_{DD} = 48\text{ V}$, $I_{DQA} = 100\text{ mA}$, $V_{GSB} = -3.5\text{ V}$, $P_{out} = 14\text{ W Avg.}$, $f = 2515 - 2675\text{ MHz}$, 1-Carrier W-CDMA, IQ Magnitude Clipping, input signal PAR = 7.5 dB @ 0.01 % Probability on CCDF. ACPR measured in 3.84 MHz Channel Bandwidth @ $\pm 5\text{ MHz}$ Offset.

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Typical RF Performance in Load Pull System

Table 7. Side A, Carrier Load Pull Performance

$V_{DD} = 48\text{ V}$, $I_{DQA} = 125\text{ mA}$, Pulsed CW, Pulse Width = 100 us, Duty Cycle = 10 %

Maximum Output Power						
Freq (MHz)	Zsource (Ω)	Zload (Ω)	Gain (dB)	Psat (dBm)	Psat (W)	η_D (%)
2500	4.0 - j16.7	11.6 - j0.4	18.2	47.7	57	69.7
2600	4.0 - j16.4	11.1 - j0.6	18.3	47.5	56	69.3
2700	3.6 - j15.5	11.8 - j0.6	18.3	47.4	55	68.0
Maximum Drain Efficiency						
Freq (MHz)	Zsource (Ω)	Zload (Ω)	Gain (dB)	Psat (dBm)	Psat (W)	η_D (%)
2500	4.0 - j16.7	4.7 + j3.1	20.2	46.1	41	79.6
2600	4.0 - j16.4	4.6 + j2.7	20.4	46.0	40	80.9
2700	3.6 - j15.5	4.1 + j2.3	20.8	45.7	37	79.7

Table 8. Side B, Peaking Load Pull Performance

$V_{DD} = 48\text{ V}$, $I_{DQB} = 200\text{ mA}$, Pulsed CW, Pulse Width = 100 us, Duty Cycle = 10 %

Maximum Output Power						
Freq (MHz)	Zsource (Ω)	Zload (Ω)	Gain (dB)	Psat (dBm)	Psat (W)	η_D (%)
2500	6.3 - j20.0	7.2 - j3.0	19.1	50.1	102	67.1
2600	9.6 - j23.5	6.5 - j3.0	19.6	50.0	100	70.9
2700	11.3 - j23.0	6.0 - j3.6	19.7	50.0	100	70.9
Maximum Drain Efficiency						
Freq (MHz)	Zsource (Ω)	Zload (Ω)	Gain (dB)	Psat (dBm)	Psat (W)	η_D (%)
2500	6.3 - j20.0	3.8 + j0.7	21.3	48.4	69	79.4
2600	9.6 - j23.5	3.8 + j0.3	21.7	48.2	66	78.6
2700	11.3 - j23.0	3.2 - j0.8	21.7	48.2	66	78.7

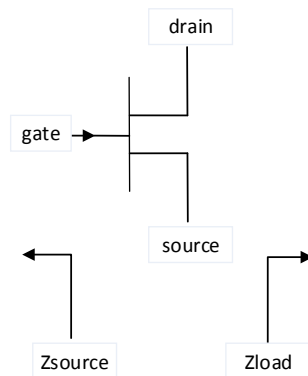


Figure 2. Definition of Transistor Impedance

Zsource: Measured impedance presented to the input of the device at the package plane

Zload: Measured impedance presented to the output of the device at the package plane

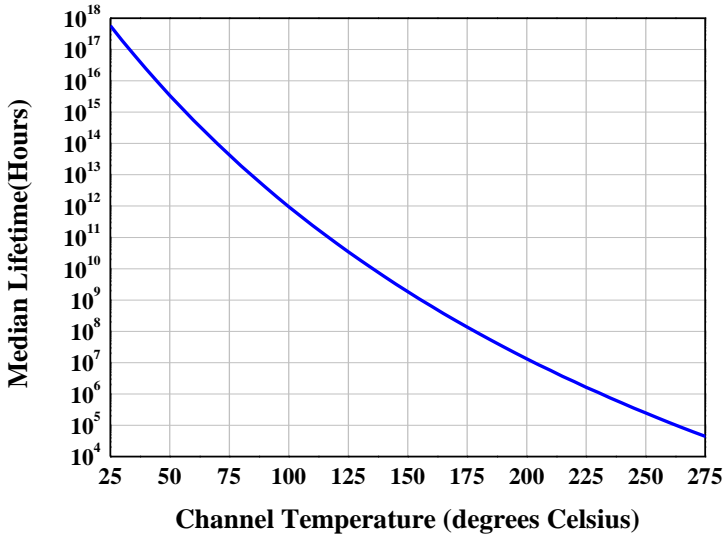
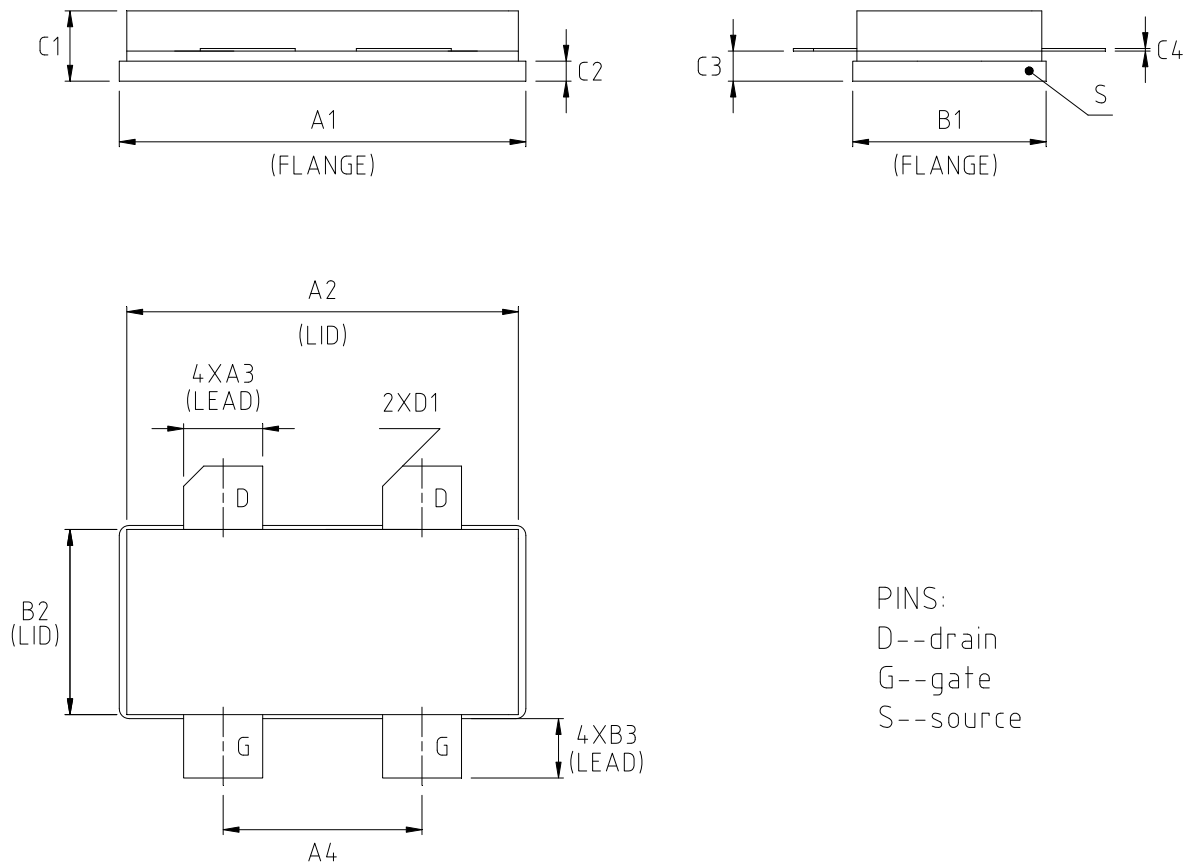


Figure 3. Median Lifetime vs. Channel Temperature

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Package Dimensions

Package Type: 780P2GB



DIM	INCH		MILLIMETER	
	MIN	MAX	MIN	MAX
A1	0.805	0.815	20.45	20.70
A2	0.772	0.788	19.61	20.02
A3	0.153	0.162	3.87	4.13
A4	0.385	0.395	9.77	10.03
B1	0.380	0.390	9.65	9.91
B2	0.365	0.375	9.27	9.53
B3	0.108	0.128	2.75	3.25
C1	0.130	0.170	3.30	4.32
C2	0.035	0.045	0.89	1.14
C3	0.057	0.067	1.45	1.70
C4	0.003	0.006	0.08	0.15
D1	0.040 45° REF		1.02 45° REF	

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Product Documentation and Software

Refer to the following resources to aid your design process.

Application Notes

- AN_04: Referential design of bias circuits of GaN HEMT transistor

Document Revision History

The following table summarizes revisions to this document.

Revision	Date	Status	Description
V1	20190726	Preliminary datasheet	Initial version.
V2	20191120	Preliminary datasheet	Update performance data.

Abbreviations

Acronym	Description
CW	Continuous Waveform
ESD	Electro-Static Discharge
GaN	Gallium Nitride
HEMT	High Electron Mobility Transistor
MTTF	Median Time To Failure
VSWR	Voltage Standing-Wave Ratio

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